## **Texas Instruments**

## **Reliability Estimator**

	Early life failure rate			Early life failure rate supporting data				MTBF / FIT supporting data						
Part number	ELFR- DPPM	MTBF	FIT	Conf level (%)	Test temp (°C)	Sample size	Fails	Usage temp (°C)	Conf level (%)	Activation energy (eV)	temp	Test duration (hours)	Sample size	Fails
TPS51200DRCR	6	1x 10	0.1	60	125	150108	0	55	60.0	0.7	125	1000	159230	0

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